

<IGBT Modules>

## **CM200DY-34T**

HIGH POWER SWITCHING USE INSULATED TYPE



dual switch (half-bridge)

- •Flat base type
- Copper base plate (Nickel-plating)
- Nickel-plating tab terminals
- RoHS Directive compliant
- •UL Recognized under UL1557, File No.E323585

#### **APPLICATION**

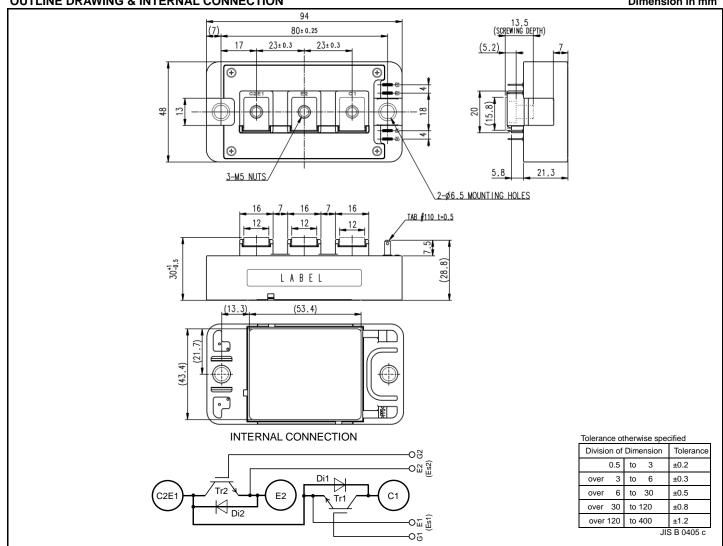
AC Motor Control, Motion/Servo Control, Power supply, etc.

**OPTION** (Below options are available.)

- •PC-TIM (Phase Change Thermal Interface Material) pre-apply
- •V<sub>CEsat</sub> selection for parallel connection

#### **OUTLINE DRAWING & INTERNAL CONNECTION**

Dimension in mm



1

#### HIGH POWER SWITCHING USE

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#### MAXIMUM RATINGS ( $T_{vj}$ =25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	1700	V	
$V_{GES}$	Gate-emitter voltage	C-E short-circuited	± 20	V	
Ic	Callagton augment	DC, Tc=134 °C* (Note2, 4)	200	^	
I <sub>CRM</sub>	Collector current	Pulse, Repetitive (Note3)	400	1 A	
P <sub>tot</sub>	Total power dissipation	T <sub>C</sub> =25 °C (Note2, 4)	2270	W	
I <sub>E</sub> (Note1)	Facition occurrent	DC (Note2)	200	^	
I <sub>ERM</sub> (Note1)	Emitter current	Pulse, Repetitive (Note3)	400	Α	
V <sub>isol</sub>	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V	
T <sub>vjmax</sub>	Maximum junction temperature	Instantaneous event (overload)	175	°C	
T <sub>Cmax</sub>	Maximum case temperature				
T <sub>vjop</sub>	Operating junction temperature	Continuous operation (under switching)	-40 ~ +150	°C	
T <sub>stg</sub>	Storage temperature	-	-40 ~ +150*		

#### ELECTRICAL CHARACTERISTICS (Tvj=25 °C, unless otherwise specified)

Cumbal	Itom	Item Conditions		Limits			Linit
Symbol	item			Min.	Тур.	Max.	Unit
CES	Collector-emitter cut-off current	V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited		-	-	1.0	m/
I <sub>GES</sub>	Gate-emitter leakage current	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited		-	-	0.5	μA
$V_{GE(th)}$	Gate-emitter threshold voltage	I <sub>C</sub> =20 mA, V <sub>CE</sub> =10 V		5.4	6.0	6.6	V
		I <sub>C</sub> =200 A, V <sub>GE</sub> =15 V,	T <sub>vj</sub> =25 °C	-	2.05	2.50	V
V <sub>CEsat</sub>		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	2.50	-	
(Terminal)		(Note5)	T <sub>vj</sub> =150 °C	-	2.60	-	
	Collector-emitter saturation voltage	I <sub>C</sub> =200 A,	T <sub>vj</sub> =25 °C	-	1.95	2.35	
V <sub>CEsat</sub>		V <sub>GE</sub> =15 V,	T <sub>vj</sub> =125 °C	-	2.35	-	V
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	2.45	-	
Cies	Input capacitance			-	-	55	
Coes	Output capacitance	V <sub>CE</sub> =10 V, G-E short-circuited	V <sub>CE</sub> =10 V, G-E short-circuited		-	1.4	nF
Cres	Reverse transfer capacitance			-	-	0.5	
Q <sub>G</sub>	Gate charge	V <sub>CC</sub> =1000 V, I <sub>C</sub> =200 A, V <sub>GE</sub> =15 V		-	1.6	-	μC
t <sub>d(on)</sub>	Turn-on delay time			-	-	800	
tr	Rise time	Vcc=1000 V, Ic=200 A, V <sub>GE</sub> =±15 V,	-	-	200		
t <sub>d(off)</sub>	Turn-off delay time			-	-	800	ns
t <sub>f</sub>	Fall time	$R_{G}=0 \Omega$ , inductive load	$R_G=0 \Omega$ , Inductive load		-	600	
(Note 4)	Emitter-collector voltage	I <sub>E</sub> =200 A, G-E short-circuited,	T <sub>vj</sub> =25 °C	-	2.75	3.35	V
V <sub>EC</sub> (Note.1)		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	3.00	-	
(Terminal)		(Note5)	T <sub>vj</sub> =150 °C	-	3.00	-	
(Note 4)		I <sub>E</sub> =200 A,	T <sub>vj</sub> =25 °C	-	2.65	3.20	
V <sub>EC</sub> (Note.1)		G-E short-circuited,	T <sub>vj</sub> =125 °C	-	2.75	-	V
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	2.75	-	
t <sub>rr</sub> (Note1)	Reverse recovery time	V <sub>CC</sub> =1000 V, I <sub>E</sub> =200 A, V <sub>GE</sub> =±15 V,		-	-	300	ns
Q <sub>rr</sub> (Note1)	Reverse recovery charge	$R_G=0 \Omega$ , Inductive load		-	10	-	μ(
Eon	Turn-on switching energy per pulse	$V_{CC}$ =1000 V, $I_{C}$ = $I_{E}$ =200 A, $V_{GE}$ =±15 V, $R_{G}$ =0 $\Omega$ , $T_{vj}$ =150 °C,		-	56.3	-	
E <sub>off</sub>	Turn-off switching energy per pulse			-	52.4	-	m
E <sub>rr</sub> (Note1)	Reverse recovery energy per pulse	Inductive load		-	22.7	-	m
R <sub>CC'+EE'</sub>	Internal lead resistance	Main terminals-chip, per switch, T <sub>C</sub> =25 °C (Note4)		-	0.3	-	m!
r <sub>g</sub>	Internal gate resistance	Per switch		-	3.8	-	Ω

<sup>\*:</sup> The value of PC-TIM applied module is limited by the heat resistant temperature of PC-TIM.

#### HIGH POWER SWITCHING USE

#### INSULATED TYPE

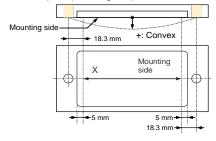
#### THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
	item	Conditions	Min.	Тур.	Max.	Offit
$R_{th(j-c)Q}$	The amount manisters as	Junction to case, per Inverter IGBT (Note4)	-	-	66.0	K/kW
$R_{th(j-c)D}$	Thermal resistance	Junction to case, per Inverter FWD (Note4)	-	-	91.9	r/KVV
R <sub>th(c-s)</sub>	Contact thermal resistance	Case to heat sink, per 1 module  Thermal grease applied (Note4, 6)	-	24.0	-	K/kW

#### **MECHANICAL CHARACTERISTICS**

Symbol	Item	Conditions		Limits			Unit
	nem			Min.	Тур.	Max.	Unit
M <sub>t</sub>	Mounting torque	Main terminals	M 5 screw	2.5	3.0	3.5	N∙m
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m
۵	Creepage distance	Terminal to terminal		18	-	-	mm
d <sub>s</sub>		Terminal to base plate		21.1	-	-	
da	Clearance	Terminal to terminal		9.6	-	-	
	Clearance	Terminal to base plate		16.7	-	-	mm
ec	Flatness of base plate	On the centerline X, Y (Note7)		±0	-	+200	μm
m	mass	-		-	155	-	g

- \*: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU.
- Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).
  - 2. Junction temperature  $(T_{vj})$  should not increase beyond  $T_{vjmax}$  rating.
  - 3. Pulse width and repetition rate should be such that the device junction temperature  $(T_{vj})$  dose not exceed  $T_{vj\,m\,a\,x}$  rating.
  - 4. Case temperature (T<sub>C</sub>) and heat sink temperature (T<sub>S</sub>) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
  - 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
  - 6. Typical value is measured by using thermally conductive grease of  $\lambda$ =3.0 W/(m·K)/D<sub>(C-S)</sub>=50  $\mu$ m.
  - 7. The base plate (mounting side) flatness measurement points (X, Y) are shown in the following figure.



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HIGH POWER SWITCHING USE

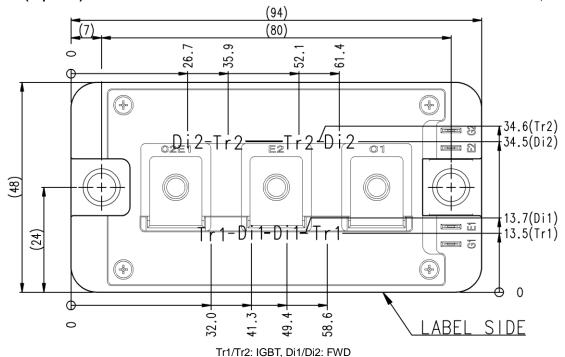
INSULATED TYPE

#### **RECMENDED OPERATING CONDITIONS**

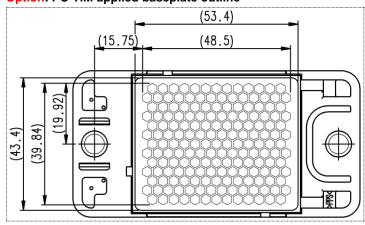
Symbol	Item	Conditions	Limits			Unit
	item		Min.	Тур.	Max.	Offic
V <sub>cc</sub>	(DC) Supply voltage	Applied across C1-E2 terminals	-	1000	1200	V
$V_{GEon}$	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R <sub>G</sub>	External gate resistance	Per switch	0	-	39	Ω

#### **CHIP LOCATION (Top view)**

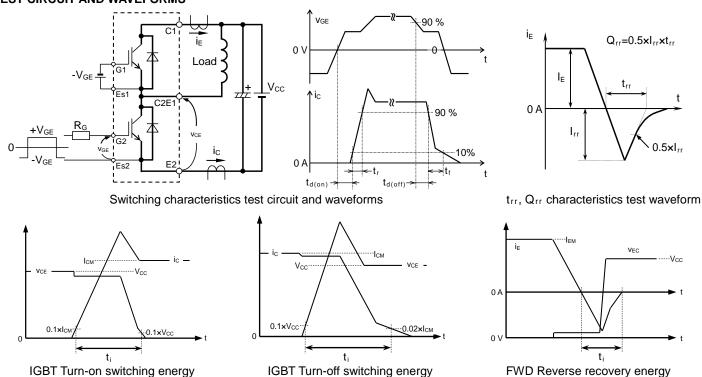
Dimension in mm, tolerance: ±1 mm



**Option: PC-TIM applied baseplate outline** 

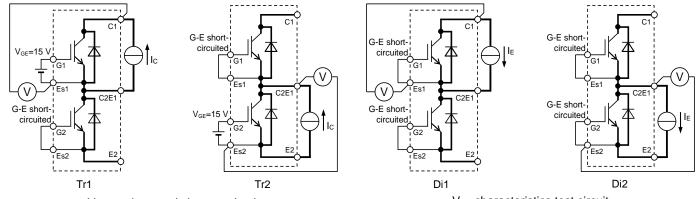


#### **TEST CIRCUIT AND WAVEFORMS**



Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

#### **TEST CIRCUIT**



V<sub>CEsat</sub> characteristics test circuit

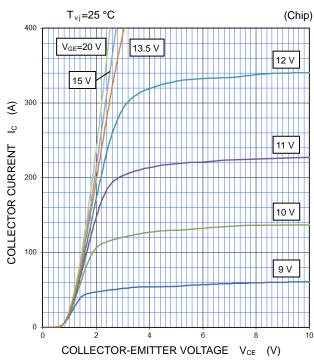
 $V_{\text{\footnotesize{EC}}}$  characteristics test circuit

HIGH POWER SWITCHING USE

INSULATED TYPE

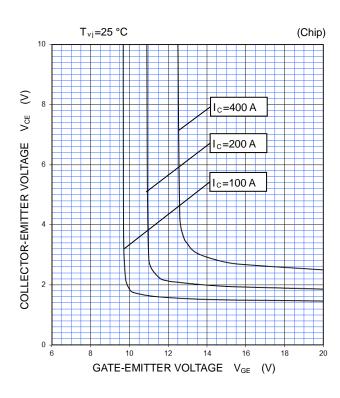
#### **PERFORMANCE CURVES**

# OUTPUT CHARACTERISTICS (TYPICAL)

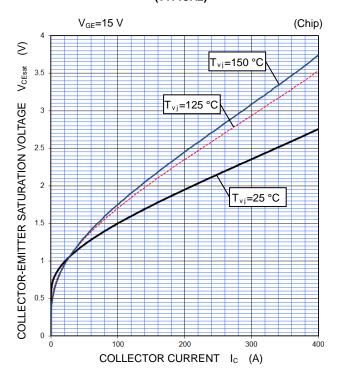


# COLLECTOR-EMITTER VOLTAGE CHARACTERISTICS

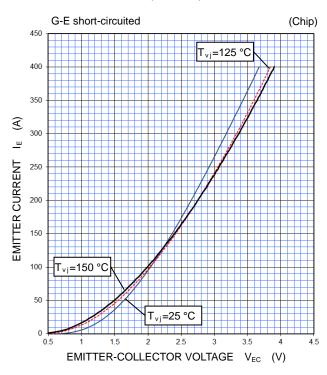
(TYPICAL)



#### COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)

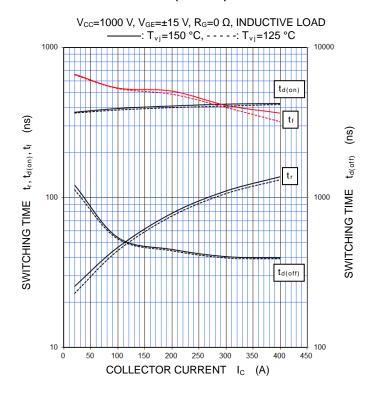


#### FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)

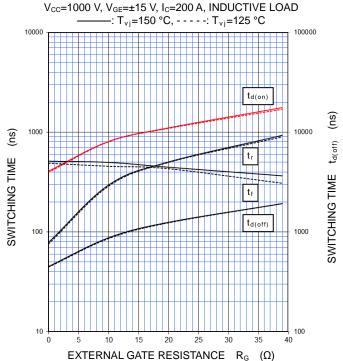


#### **PERFORMANCE CURVES**

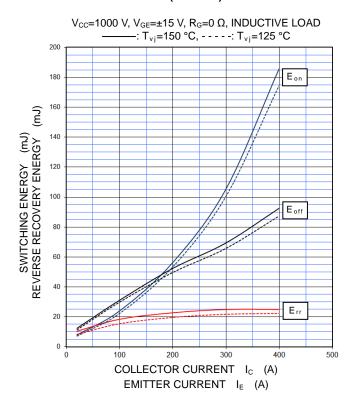
## HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



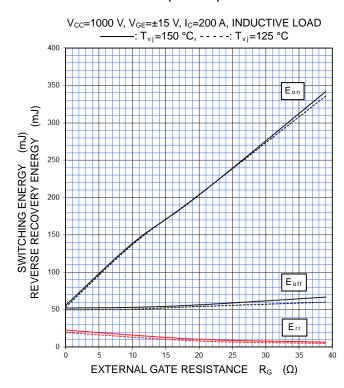
## HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



# HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

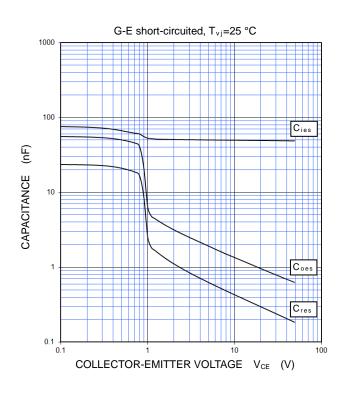


# HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

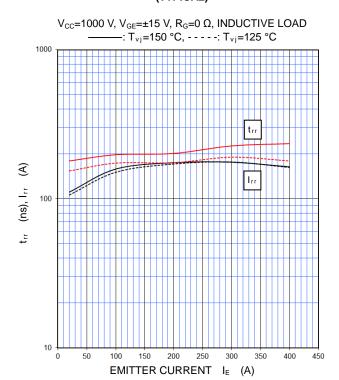


#### **PERFORMANCE CURVES**

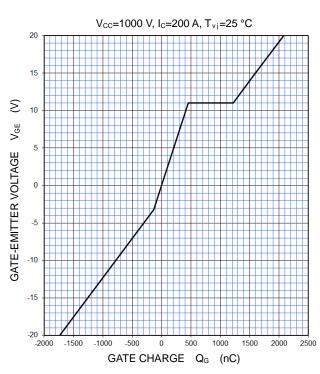
## CAPACITANCE CHARACTERISTICS (TYPICAL)



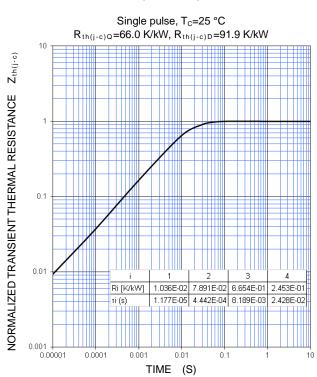
# FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)



# GATE CHARGE CHARACTERISTICS (TYPICAL)



# TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)



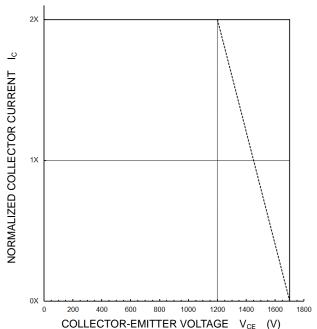
Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

HIGH POWER SWITCHING USE

INSULATED TYPE

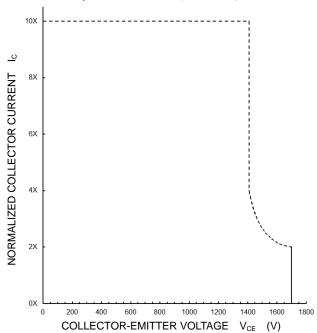
#### **PERFORMANCE CURVES**

#### TURN-OFF SWITCHING SAFE OPERATING AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM)



# SHORT-CIRCUIT SAFE OPERATING AREA (MAXIMUM)

 $V_{CC} \le 1200$  V,  $V_{GE} = \pm 15$  V,  $R_G = 0 \sim 39$   $\Omega$ ,  $T_{vj} = 25 \sim 150$  °C,  $t_W \le 8$   $\mu s$ , Non-Repetitive



HIGH POWER SWITCHING USE

**INSULATED TYPE** 

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